



Far-infrared dielectric function and phonon modes of spontaneously ordered $(Al_xGa_{1-x})_{0.52}In_{0.48}P$

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Our Messages

Far-infrared ellipsometry:

The far-infrared dielectric function of spontaneously (partially) CuPt-ordered AlGaInP has tensor character.

Observation:

Ternary and quaternary III-V-semiconductor alloys (here: AlGaInP) have ir-active lattice modes with small polarity which can not assigned to the binary components.

Conjecture:

Locally the bonding relationship (segregation, partial local ordering) fluctuates and induces lattice modes of small polarity (alloy-induced modes: AM) in the alloy.

Evidence:

The alloy-induced modes show an increasing directional response (anisotropy, transition to C_{3v} -symmetry) and polarity (TO-LO splitting) with increasing degree of ordering.

Experiment

The phonon modes with A₁- and E-symmetry in quaternary CuPt-ordered $(Al_xGa_{1-x})_{0.52}In_{0.48}P$ with 0 ... x ... 1 are determined employing far-infrared-spectroscopic ellipsometry (FIR-SE).

Frequencies of the local modes AM₁ and AM₂ correspond to ordering induced modes observed in spontaneously CuPt-ordered GaInP₂ (~ 312 cm⁻¹ und ~ 351 cm⁻¹).

MOCVD:

- ▶ $(Al_xGa_{1-x})_{0.52}In_{0.48}P$ unstrained on (001) GaAs:Te substrate with different misorientations
- ▶ T₀ = 720°C
- ▶ Al-content x=0, 0.32, 0.7, and 1

TEM:

- ▶ domain structure
- ▶ CuPt-ordering

uv-vis ellipsometry:

- ▶ layer thickness, band-band transitions
- ▶ degree of ordering

far-ellipsometry:

- ▶ phonon modes and direction dependence of phonon modes

model dielectric function:

Infrared active lattice modes

$$\epsilon^{(i)} = \epsilon_{\infty} \prod_{j=1}^n \frac{W_j^2 + i g_{L0,j} W - W_{LO,j}^2}{W^2 + i g_{TO,j} W - W_{TO,j}^2}$$

Alloy induced modes (TO-LO << TO, LO)

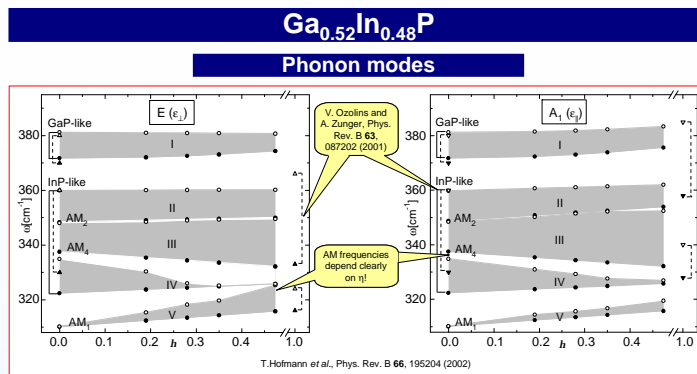
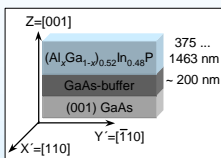
$$\epsilon^{(i) + AM}(\omega) = \epsilon^{(i)}(\omega) \prod_{k=1}^m \left(1 + \frac{i g_{AM,k} \omega - d\omega_k^2}{W^2 + i g_{AM,k} W - W_{AM,k}^2} \right)$$

Two FIR-SE measurements at different sample orientations allow the determination of the anisotropic dielectric function tensor:

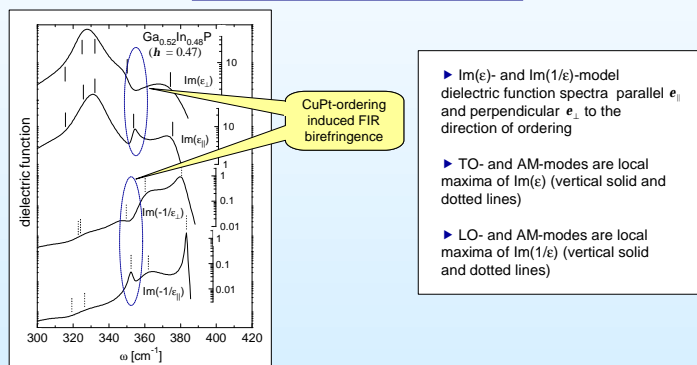
Setup A:

Setup B:

Plane of incidence perpendicular to [110] Plane of incidence parallel to [110]

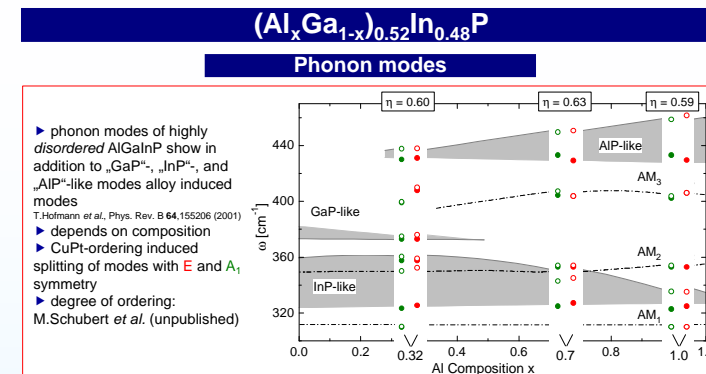
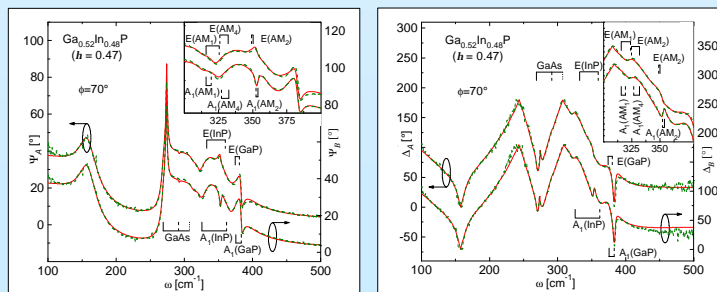


FIR-dielectric tensor

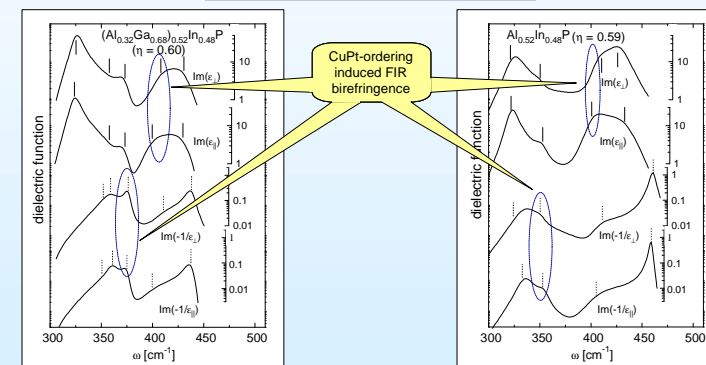


- ▶ Im(epsilon)- and Im(1/epsilon)-model dielectric function spectra parallel e₁ and perpendicular e₂ to the direction of ordering
- ▶ TO- and AM-modes are local maxima of Im(epsilon) (vertical solid and dotted lines)
- ▶ LO- and AM-modes are local maxima of Im(1/epsilon) (vertical solid and dotted lines)

FIR-SE analysis



FIR-dielectric tensor



FIR-SE analysis

